



Caltech Bruker AFM Workshop at the Kavli Nanoscience Institute



(Formerly Veeco)

AFM has been used for many years for ultra high-resolution microscopy and has earned a reputation as a powerful but complex tool. Recent advances by Bruker are making AFM easier to use, providing more unambiguous and quantitative information, and extending the ability of AFM to work with the most challenging samples. These advances include **ScanAsyst** mode with automatic image optimization technology enables easier, faster, and more consistent results in materials, life sciences, and polymer research, regardless of user skill level. A related imaging mode, **PeakForce QNM**, now provides quantitative adhesion and modulus measurements on a wide range of sample types.

Tues Jan 25 - 10:30am - 12 pm:
Technical presentation
125 Steele Laboratory

Tues Jan 25 - Wed Jan 26 - 9:00am - 4pm:
Multimode-8 demo & imaging customer samples
07 Steele Laboratory (sub-basement)

Registration and more information:

Dr. Guy DeRose
Associate Director of Technical Operations
Kavli Nanoscience Institute
California Institute of Technology
derose@caltech.edu

Mayur Savla
Sr. Applications Engineer, Bruker Corp.
Mayur.Savla@bruker-nano.com
614.209.5410

